Economics 583: Econometric Theory I A Primer on Asymptotics: Hypothesis Testing

Eric Zivot

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Hypothesis Testing

1. Specify hypothesis to be tested

 H_0 : null hypothesis versus. H_1 : alternative hypothesis

2. Specify significance level α (size) of test

$$\alpha = \Pr(\text{Reject } H_0 | H_0 \text{ is true})$$

- 3. Construct test statistic, T, from observed data
- 4. Use test statistic T to evaluate data evidence regarding H_0

T is big \Rightarrow evidence against H_0 T is small \Rightarrow evidence in favor of H_0 5. Decide to reject H_0 at specified significance level if value of T falls in the rejection region

$$T \in \text{ rejection region } \Rightarrow \text{ reject } H_0$$

Remark: Usually the rejection region of T is determined by a critical value, cv_{α} , such that

$$T > cv_{\alpha} \Rightarrow \text{reject } H_0$$

 $T \leq cv_{\alpha} \Rightarrow \text{ do not reject } H_0$

Typically, cv_{α} is the $(1-\alpha)\times 100\%$ quantile of the probability distribution of T under H_0 such that

$$\alpha = \Pr(\text{Reject } H_0 | H_0 \text{ is true}) = \Pr(T > cv_\alpha)$$

Decision Making and Hypothesis Tests

	Reality	
Decision	H_0 is true	H_0 is false
Reject H_0	Type I error	No error
Do not reject H_0	No error	Type II error

Significance Level (size) of Test

level =
$$Pr(Type \ I \ error)$$

 $Pr(Reject \ H_0|H_0 \ is \ true)$

Goal: Constuct test to have a specified small significance level

level
$$= 5\%$$
 or level $= 1\%$

Power of Test

$$power = 1 - Pr(Type II error)$$

= $Pr(Reject H_0|H_0 is false)$

or

$$Pr(Reject H_0|H_1 is true)$$

Goal: Construct test to have high power

Problem: Impossible to simultaneously have level \approx 0 and power \approx 1. As level \rightarrow 0 power also \rightarrow 0.

Example (Exact Tests in Finite Samples): Let X_1, \ldots, X_n be iid random variables with $X_i \sim N(\mu, \sigma^2)$. Consider testing the hypotheses

$$H_0: \mu = \mu_0 \text{ vs. } H_1: \mu > \mu_0$$

One potential test statistic is the t-statistic

$$t_{\mu=\mu_0} = rac{\hat{\mu} - \mu_0}{\mathsf{SE}(\hat{\mu})}$$
 $\hat{\mu} = rac{1}{n} \sum_{i=1}^n X_i, \ \mathsf{SE}(\hat{\mu}) = rac{\sigma}{\sqrt{n}}$

Intuition: We should reject H_0 if $t_{\mu=\mu_0} >> 0$.

Result: For any fixed n, under H_0 : $\mu = \mu_0$

$$t_{\mu=\mu_0} = rac{\hat{\mu} - \mu_0}{\mathsf{SE}(\hat{\mu})} = rac{1}{\sqrt{n}} \sum_{i=1}^n \left(rac{X_i - \mu_0}{\sigma}
ight) \sim N(\mathbf{0}, \mathbf{1})$$

Remarks

- 1. The finite sample distribution of $t_{\mu=\mu_0}$ is N(0,1), which is independent of the population parameters μ_0 and σ (sometimes called *nuisance* parameters). When a test statistic does not depend on nuisance parameters, it is called a *pivotal statistic* or *pivot*.
- 2. Let $\alpha \in (0,1)$ denote the significance level (size). Because we have a one-sided test, the rejection region is determined by the critical value cv_{α} such that

$$Pr(Reject\ H_0|H_0\ is\ true) = Pr(Z > cv_\alpha) = \alpha$$

where $Z\sim N(0,1)$. Hence, cv_{α} is the $(1-\alpha)\times 100\%$ quantile of the standard normal distribution. For example, if $\alpha=0.05$ then $cv_{.05}=1.645$.

- 3. The t-test that rejects when $t_{\mu=\mu_0}>cv_{\alpha}$ is an exact size α finite sample test.
- 4. We can calculate the finite sample distribution of $t_{\mu=\mu_0}$ because we made a number of very strong assumptions: X_1,\ldots,X_n be iid random variables with $X_i\sim N(\mu,\sigma^2)$. In particular, if X_i is not normally distributed then $t_{\mu=\mu_0}$ will not be normally distributed.

Example Continued: Computing Finite Sample Power

Recall,

power =
$$Pr(Reject H_0|H_1 is true)$$

To compute power, one has to specify H_1 . Suppose

$$H_1: \mu = \mu_1 > \mu_0$$

Then

power =
$$\Pr\left(\frac{\hat{\mu} - \mu_0}{\mathsf{SE}(\hat{\mu})} > cv_{\alpha} \mid H_1 : \mu = \mu_1\right)$$

Under $H_1: \mu = \mu_1$,

$$\frac{\hat{\mu} - \mu_0}{\mathsf{SE}(\hat{\mu})} = \frac{\hat{\mu} - \mu_1 + \mu_1 - \mu_0}{\mathsf{SE}(\hat{\mu})} = \frac{\hat{\mu} - \mu_1}{\mathsf{SE}(\hat{\mu})} + \frac{\mu_1 - \mu_0}{\mathsf{SE}(\hat{\mu})}$$
$$= Z + \delta \sim N(\delta, 1)$$

where

$$Z = rac{\hat{\mu} - \mu_1}{\mathsf{SE}(\hat{\mu})} \sim N(0, 1)$$
 $\delta = rac{\mu_1 - \mu_0}{\mathsf{SE}(\hat{\mu})} = \sqrt{n} \left(rac{\mu_1 - \mu_0}{\sigma}
ight)$

Therefore, under H_1 : $\mu = \mu_1$

$$\begin{array}{ll} \mathsf{power} &=& \mathsf{Pr}\left(\frac{\hat{\mu} - \mu_0}{\mathsf{SE}(\hat{\mu})} > cv_\alpha \,| H_1 : \mu = \mu_1\right) \\ &=& \mathsf{Pr}(Z + \delta > cv_\alpha) = \mathsf{Pr}(Z > cv_\alpha - \delta) \end{array}$$

Remark:

- 1. Power is monotonic in δ .
- 2. For any fixed alternative $\mu_1 > \mu_0$, as $n \to \infty$

$$\delta = \sqrt{n} \left(\frac{\mu_1 - \mu_0}{\sigma} \right) \to \infty$$

and power \rightarrow 1.

Hypothesis Testing Based on Asymptotic Distributions

- Statistical inference in large-sample theory (asymptotic theory) is based on test statistics whose asymptotic distributions are known under the truth of the null hypothesis
- The derivation of the distribution of test statistics in large-sample theory is much easier than in finite-sample theory because we only care about the large-sample approximation to the unknown finite sample distribution
 - the LLN, CTL, Slutsky's Theorem and the Continuous Mapping Theorem (CMT) allow us to derive asymptotic distributions fairly easily

Example (Asymptotic tests). Let X_1, \ldots, X_n be a sequence of covariance stationary and ergodic random variables with $E[X_i] = \mu$ and $var(X_i) = \sigma^2$. We can write

$$X_i = \mu + \varepsilon_i$$

where ε_i is a covariance stationary MDS with variance σ^2 .

Consider testing the hypotheses

$$H_0: \mu = \mu_0 \text{ vs. } H_1: \mu \neq \mu_0$$

Two asymptotic test statistics are the asymptotic t-statistic and Wald statistic

$$t_{\mu=\mu_0} = \frac{\hat{\mu} - \mu_0}{\widehat{\mathsf{ase}}(\hat{\mu})}, \,\, \mathsf{Wald} = \left(t_{\mu=\mu_0}\right)^2 = \frac{(\hat{\mu} - \mu_0)^2}{\widehat{\mathsf{avar}}(\hat{\mu})}$$

$$\hat{\mu} = \frac{1}{n} \sum_{i=1}^n X_i, \,\, \widehat{\mathsf{ase}}(\hat{\mu}) = \frac{\hat{\sigma}}{\sqrt{n}}, \,\, \hat{\sigma}^2 = \frac{1}{n} \sum_{i=1}^n (X_i - \hat{\mu})^2$$

The CLT for stationary and ergodic MDS can be used to show that under $H_0: \mu = \mu_0$

$$\hat{\mu} \stackrel{A}{\sim} N(\mu_0, \widehat{\text{avar}}(\hat{\mu})), \ \widehat{\text{avar}}(\hat{\mu}) = \frac{\hat{\sigma}^2}{n}$$

The Ergodic theorem and Slutsky's theorem can be used to show that

$$t_{\mu=\mu_0} \stackrel{A}{\sim} N(0,1) = Z$$

Additionally, the CMT can be used to show that

Wald
$$= \left(t_{\mu=\mu_0}\right)^2 \stackrel{A}{\sim} \chi^2(1) = \chi$$

If the significance level of each test is 5%, then the asymptotic critical values are determined by

t-test : $Pr(|Z| > cv_{.05}) = 0.05 \Rightarrow cv_{.05} = 1.96$

Wald test : $Pr(\chi > cv_{.05}) = 0.05 \Rightarrow cv_{.05} = 3.84$

Remarks:

- 1. The asymptotic t-test is different from the finite sample t-test in two respects:
 - (a) The way the standard error is computed $(\widehat{ase}(\hat{\mu}) \text{ vs. } \mathbf{se}(\hat{\mu}))$
 - (b) The actual size (significance level) of the asymptotic test is 5% (the nominal significance level) only as $n \to \infty$. In finite samples, the actual size of the asymptotic test may be smaller or larger than 5%. The difference between the actual size and the nominal size is called the *size distortion*.

Remarks continued:

2. For fixed alternatives (e.g. $H_1: \mu = \mu_1 \neq \mu_0$) The power of the asymptotic tests converge to 1 as $n \to \infty$. That is, the asymptotic tests are consistent tests. To see this, consider the t-test

$$\frac{\hat{\mu} - \mu_0}{\widehat{\mathsf{ase}}(\hat{\mu})} = \sqrt{n} \left(\frac{\hat{\mu} - \mu_0}{\hat{\sigma}} \right)$$

$$= \sqrt{n} \left(\frac{\hat{\mu} - \mu_1 + \mu_1 - \mu_0}{\hat{\sigma}} \right) = \sqrt{n} \left(\frac{\hat{\mu} - \mu_1}{\hat{\sigma}} \right) + \sqrt{n} \left(\frac{\mu_1 - \mu_0}{\hat{\sigma}} \right)$$

$$\xrightarrow{d} N(0, 1) + (\pm \infty) = \pm \infty$$

Therefore, as $n \to \infty$

power =
$$\Pr(\text{reject } H_0|H_1 \text{ is true})$$

= $\Pr\left(\left|t_{\mu=\mu_0}\right|>1.96\right)=\Pr(\infty>1.96)=1$

Remarks continued:

3. If there are several asymptotic tests for the same hypotheses, we can compare the *asymptotic power* of these tests by considering asymptotic power under so-called *local alternatives* of the form

$$H_1: \mu_1 = \mu_0 + \frac{\delta}{\sqrt{n}}, \ \delta \ \mathrm{fixed}$$

Under this local alternative we can calculate non-trivial asymptotic power. To see this consider the t-test:

$$\frac{\hat{\mu} - \mu_0}{\widehat{\mathsf{ase}}(\hat{\mu})} = \sqrt{n} \left(\frac{\hat{\mu} - \mu_0}{\hat{\sigma}} \right)$$

$$= \sqrt{n} \left(\frac{\hat{\mu} - \mu_1 + \mu_1 - \mu_0}{\hat{\sigma}} \right) = \sqrt{n} \left(\frac{\hat{\mu} - \mu_1}{\hat{\sigma}} \right) + \sqrt{n} \left(\frac{\mu_1 - \mu_0}{\hat{\sigma}} \right)$$

$$= \sqrt{n} \left(\frac{\hat{\mu} - \mu_1}{\hat{\sigma}} \right) + \sqrt{n} \left(\frac{\mu_0 + \frac{\delta}{\sqrt{n}} - \mu_0}{\hat{\sigma}} \right)$$

$$= \sqrt{n} \left(\frac{\hat{\mu} - \mu_1}{\hat{\sigma}} \right) + \frac{\delta}{\hat{\sigma}} \xrightarrow{d} N(0, 1) + \frac{\delta}{\sigma} = N \left(\frac{\delta}{\sigma}, 1 \right)$$

So that

power =
$$\Pr(\text{reject } H_0|H_1 \text{ is true})$$

= $\Pr\left(\left|N\left(\frac{\delta}{\sigma},1\right)\right| > 1.96\right)$

which depends on δ .